

RESEARCH ARTICLE - EMPIRICAL

Multitask defect prediction

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Abstract

Within-project defect prediction assumes that we have sufficient labeled data from the same project, while cross-project defect prediction assumes that we have plenty of labeled data from source projects. However, in practice, we might only have limited labeled data from both the source and target projects in some scenarios. In this paper, we want to apply multitask learning to investigate such a new scenario. To our best knowledge, this problem (ie, both the source project and the target project have limited labeled data) has not been thoroughly investigated, and we are the first to propose a novel multitask defect prediction approach MASK. MASK consists of a differential evolution optimization phase and a multitask learning phase. The former phase aims to find optimal weights for shared and nonshared information in related projects (ie, the target project and its related source projects), while the latter phase builds prediction models for each project simultaneously. To verify the effectiveness of MASK, we perform experimental studies on 18 real-world software projects and compare our approach with four state-of-the-art baseline approaches: single-task learning (STL), simple combined learning (SCL), Peters filter, and Burak filter. Experimental results show that MASK can achieve F1 of 0.397 and AUC of 0.608 on average with a few labeled data (ie, 10% of data). Across the 18 projects, MASK can outperform baseline methods significantly in terms of F1 and AUC. Therefore, by utilizing the relatedness among multiple projects, MASK can perform significantly better than the state-of-the-art methods. The results confirm that MASK is promising for software defect prediction when the source and target projects both have limited training data.

KEYWORDS

differential evolution, empirical studies, multitask learning, software defect prediction

1 | INTRODUCTION

Software defect prediction (SDP)¹⁻¹⁵ is a hot research topic in current software engineering research domain, and it can help to optimize test resource allocation by predicting defect-prone modules (the granularity of the module can be set as file, class, code change as needed) in advance.¹⁶ A number of defect prediction approaches have been proposed, and these approaches mainly apply machine learning techniques to build prediction models by mining data stored in software historical repositories.¹⁷⁻²¹ These approaches typically use various features (ie, metrics) to measure extracted modules from repositories and then apply machine learning algorithms to predict if a new module is defective or not. Most of the proposed approaches work on within-project defect prediction (WPDP) scenario, ie, the prediction models are trained and then applied to modules from the same project. These WPDP approaches require sufficient labeled (historical) data from a project.

However, in practice, it is rare that sufficient labeled data is available for a new project. Thus, researchers focus on cross-project defect prediction (CPDP) scenario,^{6,22-26} which builds a model using labeled data from other projects (ie, source projects) to predict defective modules in a particular project (ie, target project). Considering the domain difference phenomenon between the source and target projects, a defect prediction model trained on some projects might not generalize well to other projects.²⁷ Thus, transfer learning approaches, which aim to alleviate the differences between different projects, have been widely used to address the CPDP problem.^{6,22-26,28}

In the WPDP scenario, we assume that we have sufficient labeled data from the same project. In the CPDP scenario, we assume that we have plenty of labeled data from other projects. However, in practice, we might only have limited labeled data from both the source and target projects. Considering the following usage scenario:

Usage scenario. Bob joined a start-up company on blockchain, and the company has a number of new projects. Bob was asked to identify defective files in these projects. One challenge was that all of these projects have limited labeled data. Thus, Bob performed CPDP by using source projects from PROMISE* repository. However, preliminary results showed that the performance is very low due to the fact that their projects worked on different domains when compared with the projects from PROMISE repository. After discussing with the technical director, they decided to only use the projects in their company to perform defect prediction. Then, the core problem they meet is that:

How to perform defect prediction when both the source and target projects have limited labeled data?

In the machine learning community, multitask learning (MTL)²⁹⁻³⁵ is a kind of technique that can be used to solve this problem. MTL is one of the most active research topics in machine learning community. It aims to leverage useful information contained in multiple tasks to help improving the generalization performance of all the tasks. Among these learning tasks, a subset or all of them are assumed to be related to each other. Fortunately, there exists some relatedness between different projects. For example, projects from the same department in the organization may have the same code style and code specification.

In this paper, we propose a novel defect prediction approach MASK (Multi-tASK defect prediction) based on MTL. Our approach can effectively address the issue of training data insufficiency and make an improvement on performance. By using the information from related projects, each project equally has enough labeled modules. MASK builds models for each learned project by extracting common knowledge among all projects and personalized knowledge for each project. Besides, differential evolution optimization (DEO)³⁶ is used by MASK to search for the optimal value of regularization parameters for the common knowledge and the personalized knowledge during the process of prediction model building.

To verify the effectiveness of our proposed MASK, we compare our approach with four state-of-the-art baseline approaches: single-task learning (STL), simple combined learning (SCL) proposed by Zimmermann et al,²⁷ Peters filter proposed by Peters et al,³⁷ and Burak filter proposed by Turhan et al.¹⁶ We use 18 widely used open-source projects, which contain a total of 9393 modules, as our empirical subjects. Experimental results show that MASK can obtain the best performance on average. In particular, MASK achieves F1 of 0.397 and AUC of 0.608 on average when only 10% of data is labeled. Across the 18 projects, MASK improves the F1 of STL, SCL, Peters filter, and Burak filter by 9.07%, 49.25%, 33.67%, and 35.96% on average, and AUC of these baseline approaches by 23.42%, 36.85%, 32.20%, and 16.52% at most, respectively. Moreover, results of statistical testing based on Wilcoxon signed-rank test with a Bonferroni correction show that the improvements of our proposed method are statistically significant and the effect sizes are nonnegligible. We also investigate the influence of different percentages of labeled modules on the performance of MASK and we find that the more high-quality labeled modules, the higher performance of MASK.

Based on the above analysis, we find that treating multiple related projects simultaneously can effectively increase the size of training set for each project by considering the other projects and further improve the prediction performance. Therefore, MASK is a promising solution to solve the problem in our proposed new usage scenario that both the source and target projects have limited training data. It is not hard to find that the performance of MASK still has a certain distance from the satisfactory result. However, this is the first paper to address the issue of insufficient labeled modules by using MTL, and our study can encourage more researchers to propose more novel solutions based on MTL to further improve the performance.

The main contributions of the paper can be summarized as follows:

- To our best knowledge, we are the first to propose a new usage scenario for SDP. In this scenario, both the source and target projects have limited labeled data. To solve this issue, we propose a novel approach MASK, which utilizes the advantages of DEO and MTL to build prediction models simultaneously for related projects.
- We conduct empirical studies based on real-world software projects to demonstrate the effectiveness of MASK. The final experimental results show that our approach can achieve a significant improvement over state-of-the-art baseline approaches.

The rest of this paper is organized as follows: Section 2 introduces the motivation and preliminary of MTL. Section 3 describes our proposed MASK in detail. Section 4 introduces the empirical study, including experimental setup, the datasets, research questions, and results analysis. Section 5 discusses the limitation and computational cost of MASK. Section 6 briefly reviews related work, and finally Section 7 concludes the paper and discusses some future work.

2 | MOTIVATION AND BACKGROUND

In this section, we first show the motivation of using MTL in our proposed new scenario, which the source and the target projects only have limited labeled data. Then we introduce the preliminary of MTL to facilitate the subsequent introduction of our proposed approach.

* <http://openscience.us/repo>.

2.1 | Motivation

In practice, both the source and target projects may have limited labeled data, which hinders the use of WPDP and CPDP. An example of this usage scenario can be found in Section 1. Therefore, a new approach to solve the problem in this usage scenario is urgently required. MTL is such an ideal candidate technique, which treats related projects simultaneously by extracting and utilizing appropriate shared information among them. On the contrary, previous studies^{6,37-41} simply treated these projects independently and ignored the relatedness among projects, which can be called as single-task learning (STL). Figure 1 illustrates the difference between STL and MTL. For STL, each project is considered to be independent and learned independently. For MTL, multiple projects are considered together and learned simultaneously by utilizing the relatedness of these projects. Notice that by extracting and utilizing appropriate shared information among related projects, MTL outputs multiple models since each project also has its characteristics. Therefore, building multiple personalized models rather than one generalized model can make full use of characteristics and may have the potential to improve the performance.

MTL is inspired by human learning activities, in which people often apply knowledge learned from previous tasks to learn a new task. For example, when a person learns to ride the bicycle and tricycle together, the experience in learning to ride the bicycle can be utilized in riding the tricycle and vice versa, since the bicycle and the tricycle are related to each other. Therefore, similar to human learning, it is useful for multiple learning tasks to be learned jointly since the knowledge contained in a task can be leveraged by other tasks. Taking SDP as another example, when many new projects need defect prediction and these projects are related (eg, these projects are developed by the same company for the same target), the rules learned in building a model on one project can be utilized to build a model on another project and vice versa.

The setting of MTL is similar to that of CPDP which is a specific case of transfer learning.⁴² However, there are some differences between them. In MTL, there is no distinction among different tasks, and the objective is to improve the performance of all related tasks. That is, all tasks in MTL are treated fairly. In CPDP, the source project and the target project are used to distinguish the roles of different projects, and the objective is to improve the performance of a target project with the help of the source project. That is, the target project plays a more important role than the source project. Hence, MTL treats all the projects equally but in CPDP the target project attracts more attention among all the projects.

Different from previous studies^{6,37,41} which treat each project independently, in this paper, we treat all these projects fairly and simultaneously.

2.2 | Preliminary

In this subsection, we give some definitions of MTL to illustrate our proposed MASK more clearly. More details can be found in a recent survey for MTL.³⁵

Definition 1 (MTL). Suppose there are m tasks to be learned $\{T^i\}_{i=1}^m$, where all the tasks or at least a subset of them are related, MTL aims to improve the learning of a model for T^i by using the knowledge contained in the m tasks.

In this paper, we focus on supervised learning based tasks since most studies for SDP fall into this setting. Notice that a project in SDP context is equally viewed as a task in the context of MTL.

When different projects consider the same feature space, this setting is named as the homogeneous-feature MTL, and otherwise, it corresponds to heterogeneous-feature MTL. In this paper, the MTL setting is the homogeneous-feature MTL, which means all related tasks (ie, projects) have the same feature space.

Definition 2 (Multiple classification). The simple multiple classification model (ie, a special scene of MTL) can be represented as the following: $\text{LogisticFunction}(X^i W^i + \text{Bias}^i)$, $i = 1, \dots, m$, which can build multiple classification models simultaneously.

In this definition, $X^i \in \mathbb{R}^{n^i \times F^i}$ represents the training module matrix of the i th task, where n^i and F^i represent the number of modules and the feature space respectively. $\text{Bias}^i \in \mathbb{R}^{n^i}$ is a bias vector, and $\text{LogisticFunction}(X^i W^i + \text{Bias}^i)$ represents the classification model. There are m tasks in

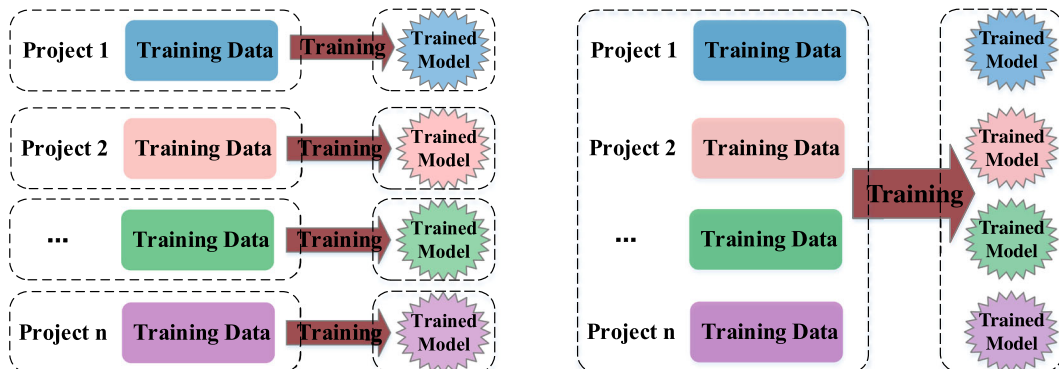


FIGURE 1 Comparison between single-task learning (STL) (left) and multitask learning (MTL) (right)

total. For the convenience of description, we transform these quantities into matrices. That is, $W \in \mathbb{R}^{F \times m}$ represents the regression parameters, and $Bias \in \mathbb{R}^{n \times m}$ represents the noise.

According to the above definitions, it is not hard to find that the parameter W is critically important since it contains the relatedness among different tasks. For convenience, we represent the parameters W as a matrix, where each column corresponds to a task, and each row to a feature. Meanwhile, not only do different tasks have a certain common knowledge (ie, shared information), but also they have personalized knowledge (ie, nonshared information). Therefore, both the shared information and nonshared information are included in the parameter W . It seems to be that any one structure might not fully capture all of that information but decomposition of structure might.³² Therefore, the matrix W should be decomposed into two component matrices *Shared* and *NonShared*, ie, $W = Shared + NonShared$. In particular, some rows of W would have many nonzero entries that correspond to features shared by several projects. We use a row-sparse³² matrix *Shared* to represent such shared information, where each row is either all zero or mostly nonzero, and the number of nonzero rows is small. Some rows of W would be project-sensitive that correspond to those features related to some projects but not all. We use an elementwise sparse matrix *NonShared* to represent such nonshared information. It is obvious that some rows of W would have all zero entries that correspond to those features that are not relevant to any projects.

3 | OUR PROPOSED MASK APPROACH

Previous approaches^{26,41} can build one defect prediction model for one target project at a time, while MASK extended from a previous study³² can build multiple defect prediction models for multiple target projects at a time. Figure 2 presents the overall framework of MASK. In this figure, for the convenience to distinguish related projects, these projects are represented with different colors, respectively. Besides, these projects are drawn in the form of three dimensions, which can easily display the format of input data. In the phase of model building, different colors are used to represent different kinds of learned information (ie, shared information and nonshared information), in which α and β are regularization parameters and their detailed introduction can be found in Section 3.1. In general, MASK mainly contains two phases: a DEO phase and a MTL phase. In the former phase, since hyperparameter optimization⁴³ has a substantial impact on the model performance and cannot be neglected, we use DEO to search for the optimal value of regularization parameters for both the shared information and nonshared information. In the latter phase, to address the issue of insufficient labeled modules, we use MTL to build models simultaneously, based on the optimal value of regularization parameters obtained by DEO. Finally, we return models for different projects.

Different from previous studies that take each project as input independently, our framework takes all related projects as a whole as the input, and it is shown in Figure 2. Some data preprocessing methods are performed on the datasets of these projects. In particular, we normalize all the numerical features by using z score. Here, the number of related projects to be learned equals to the number of models outputted by MASK. Relatedness is a core concept in MTL. In this paper, we simply consider two types of relatedness. One is whether these projects are developed by the same organization. The other is whether these projects have the same feature space. A more effective way to measure the relatedness of different projects can help improve the performance of MASK. This is still an open problem and needs more investigation in the future.

In the rest of this section, we will introduce the details of DEO phase and MTL phase in sequence.

3.1 | DEO phase

In this phase, MASK uses DEO to search for the optimal hyperparameter value for both the shared information and the nonshared information. DEO is an optimizer, which is especially suitable for functions that may not be smooth or linear. It has been widely used in previous studies for hyperparameter optimization.⁴⁴⁻⁴⁷ According to a previous study,⁴⁸ DEO has more competitive advantages when compared with other metaheuristic search algorithms, such as particle swarm optimization or genetic algorithm.

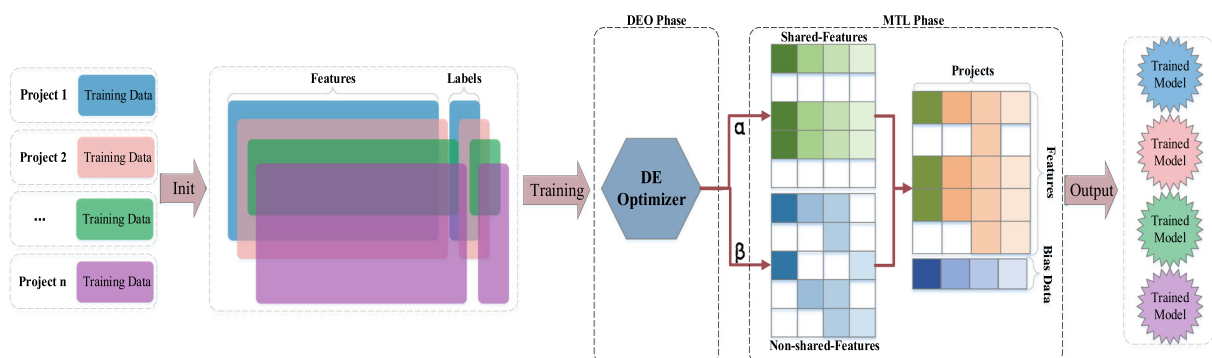


FIGURE 2 The framework of MASK

Algorithm 1 Differential Evolution Optimization Phase**Input:**

$X^{n \times F \times t}$: all the data of related projects
 n : population size
 p : crossover probability
 w : differential weight
 $lives$: number of generations

Output:

$BRP(\alpha, \beta)$: a pair of the optimal regularization parameters;

- 1: Split X into two sets: training set written as X_T and validation set written as X_V ;
- 2: Let *candidatePop* = Initial population with n chromosomes;
- 3: Build models on X_T with *candidatePop* and evaluate by AUC measure on X_V . Then record the best solution (ie, the solution with maximum AUC) found so far as *BRP*;
- 4: Let *lives* = 1;
- 5: **while** (*lives* -- > 0) **do**
- 6: **for** $i = 1$ to n **do**
- 7: P_i = the i th chromosome of *candidatePop*;
- 8: NP = Mutation(P_i, p, w);
- 9: NP = Crossover(NP, P_i, p, w);
- 10: Compare the fitness of both NP and P_i on X_V by *func*, and record the better generation;
- 11: **if** (the better generation is greater than *BRP*) **then**
- 12: Update *BRP* and allow further iteration: *lives* + +;
- 13: **end if**
- 14: **end for**
- 15: **end while**
- 16: **return** *BRP*

In Algorithm 1, DEO firstly splits all related projects X into two sets: a training set written as X_T and a validation set written as X_V (line 1). Then it randomly initializes the value of each candidate chromosome which encodes two regularization parameters (line 2). After that, these models built on X_T with n candidates chromosomes from an initial population are evaluated for the current regularization parameters on the validation data X_V . Notice that the evolution is guided by a fitness function (ie, maximizing AUC calculated by *func* in line 10) (line 3). It starts to evolve on the initial population with one *lives* (line 4). After that, DEO goes into population evolution⁴⁸ (lines 5-15). In each generation, to evolve the candidates, DEO compares the fitness value (ie, AUC) of old candidates with that of the new candidates. After that, new candidates with better fitness value replace older ones (line 10). In particular, the *func* function returns the average performance of MTL (Algorithm 2) using the evolved new parameter settings. Notice that we initialize parameter *lives* with 1, which can ensure it runs into the inner of *while* loop. Besides, there also exists a *for* loop inside of the *while* loop. In the *for* loop, the differential evolution algorithm will increase the value of parameter *lives* if better generation can be found (lines 11-12). Therefore, there is at least one generation if differential evolution cannot find better generations.

When the DEO optimizer terminates, it will return the optimal value from the candidate parameter setting *BRP* (ie, two regularization parameters) obtained in all the iterations.

Tables 1 and 2 list all the important parameters in the DEO phase and the regularization parameters. Table 1 provides parameter names, their descriptions, and default values in the DEO phase. In this paper, we use the value of hyperparameters in differential evolution, which is suggested by Agrawal and Menzies.⁴⁵ Table 2 provides regularization parameter names, search ranges explored by DEO and their descriptions. Notice we use the tuning range of these regularization parameters suggested by Jalali et al.³²

Parameter Name	Description	Default Value
n	Frontier size in a generation	10
p	Survival of the candidate	0.3
w	Mutation probability	0.7
<i>lives</i>	Number of generations	1

TABLE 1 Parameters in the DEO phase

Abbreviation: DEO, differential evolution optimization.

TABLE 2 Regularization parameters in the MTL phase

Parameter Name	Tuning Range (Explored by DEO)	Description
α	[0.01, 2]	A regularization parameter for shared information
β	[0.01, 2]	A regularization parameter for nonshared information

Abbreviations: DEO, differential evolution optimization; MTL, multitask learning.

3.2 | MTL phase

Algorithm 2 presents the details on the MTL phase. MTL firstly needs to initialize the start points. In our implementation, we simply initialize the start points with zero matrices (line 1). In fact, a starting point can be initialized to a value computed from data or a specified point. It defines some important variables that can control the process of searching for the optimal value for S , NS , and B (line 2). Then MTL goes into a loop block with $maxIter$ iteration times (lines 3-15). In this loop, MTL updates *Shared*, *NonShared*, and *Bias* with the search factor α (line 4). After that, it computes the whole loss value and gradients for the current search points (line 5). Next, MTL goes further into a inner loop in which it can only be terminated until a specific termination condition is satisfied (lines 6-12). In this inner loop, the same normalization operations³² are used on the shared and nonshared information parameters together with the optimal bias data, and the Armijo Goldstein line search scheme⁴⁹ is used to speed up search efficiency (lines 7-9). MTL then calculates the performance of current parameters and records the performance (line 10). When satisfying the termination condition of the inner loop, it backs up previous search points, does preparation for the next iteration, and jumps out of the inner loop block (line 11). If the difference between the latest two performance values meets the requirements of maximum tolerance, MTL can jump out of the outer loop block and end in advance (line 13). If not, MTL will go to the next iteration with the updated change factor (ie, t' , t) (line 14). At last, it returns the optimal value for S , NS , and B calculated by a certain number of iterations (line 16).

Algorithm 2 Multiple Tasks Learning Phase

Input:

$X^{n \times F \times t}$: all the data of related projects
 $Y^{n \times 1 \times t}$: the corresponding true labels of all related projects
 BRP : the output of DEO
 $maxIter$: the number of maximum iterations
 $maxTol$: the tolerance of the performance between two iteration

Output:

$Shared^{F \times t}(S)$: all shared information among projects
 $NonShared^{F \times t}(NS)$: nonshared information for each project
 $Bias^{t \times 1}(B)$: the bias data for classification

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1: Initialization the start point: filling Shared, NonShared, Bias with a zero matrix;
2: Let  $t=1$ ,  $t' = iter = 0$ ,  $\gamma = 1$ ,  $\gamma_{inc} = 2$ ,  $\alpha$  = Initial search factor, which controls the search for optimal  $S$ ,  $NS$ ,  $B$ ;
3: while ( $iter < maxIter$ ) do
4:   Set  $\alpha = (t' - 1)/t$ , then find next search point for  $S$ ,  $NS$ ,  $B$  with  $\alpha$ , and store them into  $S_{tmp}$ ,  $NS_{tmp}$ ,  $B_{tmp}$ ;
5:   Compute the whole loss value with regularization parameters stored in  $BRP$  and gradients of the current search point with  $S_{tmp}$ ,  $NS_{tmp}$ , and  $B_{tmp}$ ;
6:   while (True) do
7:     process proximal  $l_1 - norm$  and  $l_\infty - norm$  on  $S_{tmp}$  in turn, and return  $S_t$ ;
8:     process proximal  $l_1 - norm$  and  $l_1 - norm$  on  $NS_{tmp}$  in turn, and return  $NS_t$ ;
9:     Update bias vector to  $B_t$ ;
10:    Evaluate performance and save it in list of funcVal;
11:    Stop if reach termination conditions, otherwise let  $\gamma = \gamma \times \gamma_{inc}$ ;
12:  end while
13:  If reach maximum tolerance, Break;
14:  Let  $iter++$ , and update  $t'$  and  $t$ ;
15: end while
16: return  $S$ ,  $NS$ ,  $B$ 

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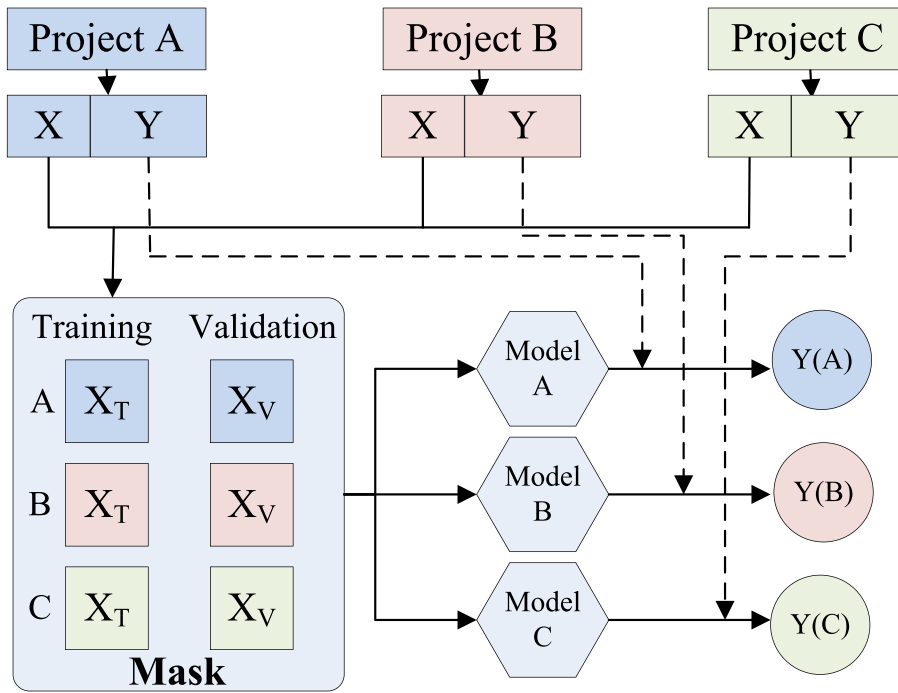


FIGURE 3 A working example when applying MASK to three related projects

3.3 | Working example of MASK

To facilitate the understanding of the process of MASK, we take a working example to illustrate how MASK works in Figure 3. Suppose there are three related projects (ie, A, B, and C) with limited labeled data, and all of these projects need defect prediction. However, we can use neither WPDP methods nor CPDP methods to build prediction models since the limitation of labeled data from source project or target projects. Therefore, we resort to MASK since it does well in such a situation that each project has a few labeled data. All three projects will be treated as the input of MASK simultaneously. MASK firstly splits the three projects into two sets, respectively: a training set X and a testing set Y .

To obtain the optimal value for hyperparameters, MASK further split X into two sets: training dataset X_T and validation dataset X_V . In this step, DEO, an optimizer, searches for the optimal value for hyperparameters on X_T and checks the validation on X_V . After DEO obtains the optimal value for hyperparameters, MASK then builds three prediction models simultaneously and predict the testing data Y , respectively.

4 | EXPERIMENT DESIGN AND RESULT ANALYSIS

In this section, we conduct empirical studies to evaluate the performance of MASK. All the approaches are executed on CentOS Linux 7 (Memory: 32 GB, Processor: Intel Xeon(R) CPU E5-2609 v2 @ 2.50 GHz × 8).

4.1 | Experimental setup

In our empirical studies, we assume that both the source and target projects have limited labeled data in our proposed new scenario. To solve the issue in this scenario, MASK based on MTL is used. Here, we treat one project in the context of SDP as one task in the context of MTL.

To evaluate the performance of MASK, we consider four baseline approaches. The first baseline approach is single-task learning (STL). This approach treats each project independently. The second baseline approach is proposed by Zimmermann et al.²⁷ This approach directly combines all related project, and we use SCL to represent this approach. The third baseline approach is Peters filter proposed by Peters et al.³⁷ The forth baseline approach is Burak filter proposed by Turhan et al.¹⁶ The last two approaches are classical module selection based CPDP approaches. Notice that we do not take TCA+³⁹ as the baseline method since it needs no labeled modules in the target project to build a prediction model but MASK does need. In addition, multilabel classification techniques⁵⁰ have been adopted into the software engineering domain. However, there also exists a difference between MTL techniques and multilabel classification techniques. In particular, multilabel classification techniques aim to deal with these issues in which modules must have at least three different types of label, while multitask classification techniques aim to build multiple defect prediction models simultaneously which is suitable for both multilabel classification issues and binary classification issues. However, for defect prediction considered in this paper, all the experimental datasets (ie, AEEEM, MORPH, and ReLink) have at most two different types of the label (ie, defectiveness or nondefectiveness). Therefore, multilabel classification techniques are not suitable for these datasets considered in the current experiment, and we do not take such techniques as the baseline methods for comparison.

For MASK, we train and test the defect prediction models on all projects simultaneously. Since we want to simulate the insufficiency of training data for a newly developed project, we use inverse 10-fold cross validation (CV). In particular, for a specific project (ie, the target project), we

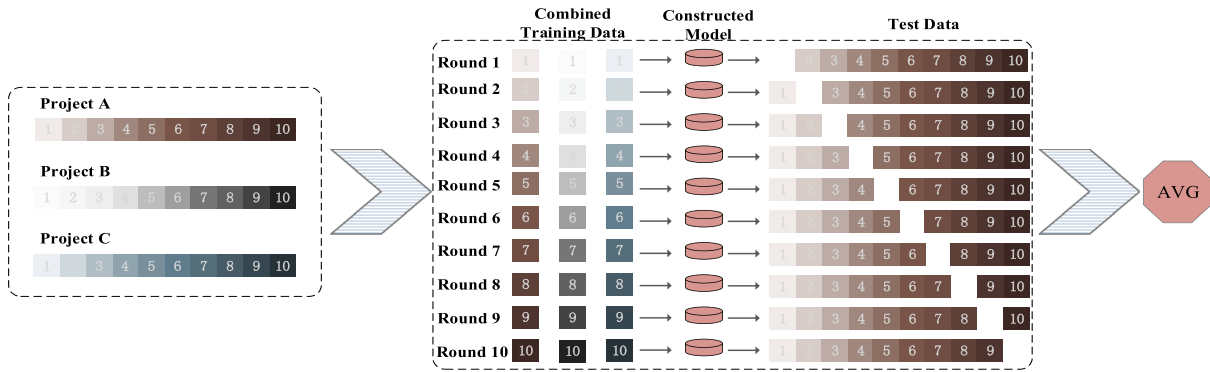


FIGURE 4 The evaluation process of inverse 10-fold cross validation

split the project into ten folds equally by using stratified sampling. Then the one fold is treated as the labeled training data, while the remaining nine folds are treated as the testing data.

For example, there are three related projects: A, B, and C. All of them are treated as the target projects since we want to do defect prediction on them independently. We first split these three datasets into 10 folds, respectively. Then the labeled training data is comprised of the i th fold of project A, the i th fold of project B, and the i th fold of project C (ie, $i \in [1, 10]$). Notice these folds are not simply combined together. After that, MASK builds three prediction models for these projects simultaneously. When predicting on project A, the prediction model built by MASK for project A is tested on the remaining nine folds of the project A. This process is repeated 10 times, and we report performance value of 10 runs on average for the project A (ie, AVG is an abbreviation for average in Figure 4). The main evaluation process of MASK can be found in Figure 4.

For STL, we also use inverse 10-fold CV to train and test defect prediction model for each project independently. For example, when performing defect prediction on the project A, STL only builds the prediction model on one fold of the project A and evaluates on the remaining nine folds. This process is repeated 10 times, and we report the average performance value of 10 runs for the project A.

For three CPDP methods (ie, SCL, Peters filter, and Burak filter), inverse 10-fold CV is performed differently. For example, there are three projects (ie, A, B, and C). We first split these three datasets into 10 folds, respectively. Then these CPDP methods combine the i th fold of the project A, the i th fold of the project B, and the i th fold of the project C as the labeled training data. Notice these folds are only simply combined together. After that, a prediction model built on the combined three folds is evaluated on the remaining nine folds of each project, respectively. This process is repeated 10 times, and we report the average performance value of 10 runs for three projects, respectively.

To overcome a possible bias in the data split processes, we perform inverse 10-fold CV for 10 times independently.

4.2 | Datasets

In the experiments, we use three widely used datasets^{25,26,39,41,52}: ReLink, AEEEM, and MORPH. Table 3 shows the characteristics of these datasets. The ReLink dataset was collected by Wu et al.⁵³ ReLink considers 26 complexity metrics as features. The metrics are designed based on the analysis on code complexity (such as LOC, cyclomatic complexity, number of classes, etc) and abstract syntax trees (such as number of blocks, number of statements, method references, etc). The AEEEM dataset was collected by D'Ambros et al.⁵⁴ AEEEM considers 61 metrics, which are categorized into source code metrics, previous-defect metrics, entropy-change metrics, and churn-of-source-code metrics. The MORPH dataset can be downloaded from PROMISE repository,[†] which considers CK-based metrics. Notice that in this paper, we assume these projects in the same dataset are developed by the same organization. Besides, the projects in the same dataset use the same metrics to measure the extracted program modules (ie, they have the same feature space). Therefore, in terms of these two heuristics (ie, the same organization and the same feature space), we assume all projects in the same dataset have a certain relatedness. For example, *Apache*, *Safe*, and *ZXing* are considered as related project since all of them belong to ReLink data set, and they have the same feature space (ie, 26 metrics).

4.3 | Performance measures

We use F1 and AUC to evaluate the performance of different approaches. According to the ground truths and the predicted class labels, we can compute the number of true positives (TP), false positives (FP), true negatives (TN), and false negatives (FN), respectively.

F1 measure, a trade-off between the precision measure (P) and the recall measure (R), is widely used to compare different defect prediction approaches,²⁶ and F1 can be computed as follows:

$$F1 = (2 \times P \times R) / (P + R). \quad (1)$$

Here, the measures P and R can be computed as follows:

$$P = TP / (TP + FP), \quad R = TP / (TP + FN). \quad (2)$$

[†]<http://openscience.us/repo>.

Datasets	Projects	# Metrics	# Modules	# (%) Defective Modules
ReLink	Apache	26	194	98 (50.52%)
	Safe		56	22 (39.29%)
	ZXing		399	118 (29.57%)
AEEEM	EQ	61	324	129 (39.8%)
	JDT		997	206 (20.7%)
	LC		691	64 (9.3%)
	ML		1,862	245 (13.2%)
	PDE		1,497	209 (14.0%)
MORPH	ant-1.3	20	125	20 (16.00%)
	arc		234	27 (11.54%)
	camel-1.0		339	13 (3.83%)
	poi-1.5		237	141 (59.49%)
	redaktor		176	27 (15.34%)
	skarbonka		45	9 (20.00%)
	tomcat		858	77 (8.97%)
	velocity-1.4		196	147 (75.00%)
	valan-2.4		723	110 (15.21%)
	xerces-1.2		440	71 (16.14%)

TABLE 3 The characteristics of datasets

Cliff's Delta(δ)	Effectiveness Level
$ \delta < 0.147$	Negligible
$0.147 \leq \delta < 0.33$	Small
$0.33 \leq \delta < 0.474$	Medium
$ \delta \geq 0.474$	Large

TABLE 4 Cliff's delta and the effectiveness level⁵¹

Different from F1, AUC measures the area under the receiver operating characteristic (ROC) curve, which is a 2D illustration of true positive rate on the y axis versus false positive rate on the x axis. ROC curve is obtained by varying the classification threshold over all possible values, separating nondefective and defective predictions. A prediction model with the best performance provides an AUC value close to 1. The ROC analysis is robust in case of imbalanced class distributions and asymmetric misclassification costs.^{43,55-58}

4.4 | Result analysis

In our empirical studies, we want to answer the following two research questions.

RQ1: *How effective is our proposed approach MASK in defect prediction? How much improvement can it achieve over the baseline approaches?*

Motivation. Our goal is to design an approach, which is applicable to new usage scenario that both source and target projects have limited labeled modules. However, to show the feasibility of this approach, this RQ is designed to find how effective it is in performing defect prediction and whether it can have better performance than baseline approaches. The answer for this RQ would shed light on how much our approach advances the state-of-the-art approaches in the defect prediction.

Approach. To answer this RQ, we compare MASK with STL, SCL, Peters filter, and Burak filter to investigate whether MASK has better performance over these baseline approaches for building defect prediction models. F1 and AUC are used to evaluate the performance of these approaches. By default, we run all these approaches 100 times independently. To check the significance of performance comparison, we conduct the Wilcoxon signed-rank test⁵⁹ with a Bonferroni correction.⁶⁰ Wilcoxon signed-rank test is a nonparametric statistical hypothesis test on the performance measures, while Bonferroni correction is used to counteract the problem of multiple comparisons. For all the statistical testings, the null hypothesis is that there is no difference between the trained prediction models, and the significance level α is set as .05. If P value is smaller than .05, we reject the null hypotheses; otherwise, we accept the null hypotheses.

We also use Cliff's delta (δ),⁵¹ which is a nonparametric effect size measure and can quantify the amount of difference between two approaches. In our context, the Cliff's delta is used to compare our proposed approach MASK with the baseline approaches. The range of Cliff's delta is $[-1, 1]$. If the absolute value of δ equals to 1, it indicates the absence of overlap between two approaches. It means all data from one group are higher than that from the other group and vice versa. If the value of δ equals to zero, it means that the two approaches are overlapping completely. Table 4 describes the meanings and corresponding interpretations when Cliff's delta has different values.⁵¹

Results. Tables 5 and 6 show the comparison results of MASK with STL and the state-of-the-art CPDP approaches (ie, SCL, Peters filter, and Burak filter) in terms of F1 and AUC, respectively. In both of the two tables, the first column presents the name of datasets. The second column lists project name. Here, we assume that the projects in the same dataset has a certain relatedness, since they consider the same metrics.

The remaining five columns list the performance values of five approaches in terms of different performance measures (ie, F1 and AUC). The results in cells are in the form of mean \pm standard deviation, which can illustrate the average performance and stability of trained models. Notice

TABLE 5 The comparison result of MASK with STL, SCL, Peters filter, and Burak filter in terms of F1

Datasets	Related Projects	MASK	STL	SCL	Peters Filter	Burak Filter
AEEEM	EQ	0.574 ± 0.061	0.529 ± 0.058	0.322 ± 0.048	0.511 ± 0.117	0.545 ± 0.134
	JDT	0.539 ± 0.090	0.404 ± 0.057	0.428 ± 0.053	0.320 ± 0.105	0.452 ± 0.143
	LC	0.365 ± 0.071	0.222 ± 0.052	0.302 ± 0.062	0.145 ± 0.081	0.299 ± 0.094
	ML	0.255 ± 0.102	0.297 ± 0.034	0.276 ± 0.035	0.231 ± 0.069	0.291 ± 0.065
	PDE	0.284 ± 0.100	0.277 ± 0.037	0.295 ± 0.039	0.188 ± 0.112	0.295 ± 0.113
Avg		0.403 ± 0.085	0.346 ± 0.048	0.325 ± 0.047	0.279 ± 0.096	0.376 ± 0.110
MORPH	ant-1.3	0.338 ± 0.137	0.289 ± 0.105	0.199 ± 0.116	0.284 ± 0.109	0.252 ± 0.142
	arc	0.270 ± 0.111	0.208 ± 0.073	0.232 ± 0.104	0.166 ± 0.093	0.063 ± 0.101
	camel-1.0	0.185 ± 0.080	0.145 ± 0.063	0.138 ± 0.067	0.080 ± 0.040	0.056 ± 0.071
	poi-1.5	0.733 ± 0.037	0.587 ± 0.060	0.089 ± 0.035	0.428 ± 0.342	0.317 ± 0.164
	redaktor	0.360 ± 0.140	0.298 ± 0.117	0.167 ± 0.097	0.222 ± 0.111	0.202 ± 0.173
	skarbonka	0.327 ± 0.136	0.337 ± 0.115	0.208 ± 0.088	0.223 ± 0.164	0.187 ± 0.160
	tomcat	0.256 ± 0.102	0.247 ± 0.060	0.300 ± 0.068	0.122 ± 0.090	0.139 ± 0.093
	velocity	0.858 ± 0.038	0.726 ± 0.091	0.067 ± 0.043	0.558 ± 0.359	0.079 ± 0.057
	xalan-2.4	0.279 ± 0.106	0.294 ± 0.055	0.205 ± 0.070	0.166 ± 0.124	0.333 ± 0.055
	xerces-1.2	0.138 ± 0.059	0.291 ± 0.057	0.124 ± 0.052	0.216 ± 0.085	0.204 ± 0.042
Avg		0.374 ± 0.095	0.342 ± 0.080	0.173 ± 0.074	0.247 ± 0.152	0.183 ± 0.106
Relink	Apache	0.617 ± 0.052	0.507 ± 0.087	0.544 ± 0.079	0.612 ± 0.084	0.611 ± 0.066
	Safe	0.545 ± 0.141	0.496 ± 0.148	0.504 ± 0.117	0.493 ± 0.209	0.543 ± 0.112
	Zxing	0.225 ± 0.109	0.395 ± 0.050	0.390 ± 0.056	0.378 ± 0.160	0.393 ± 0.057
Avg		0.462 ± 0.101	0.466 ± 0.095	0.479 ± 0.084	0.494 ± 0.151	0.516 ± 0.078
Total Avg		0.397 ± 0.093	0.364 ± 0.073	0.266 ± 0.068	0.297 ± 0.136	0.292 ± 0.102

Note. Notice the best F1 in each row is marked in bold. Abbreviations: SCL, simple combined learning; STL, single-task learning.

TABLE 6 The comparison result of MASK with STL, SCL, Peters filter, and Burak filter in terms of AUC

Datasets	Related Projects	MASK	STL	SCL	Peters Filter	Burak Filter
AEEEM	EQ	0.677 ± 0.027	0.619 ± 0.037	0.581 ± 0.018	0.621 ± 0.163	0.581 ± 0.061
	JDT	0.709 ± 0.052	0.624 ± 0.041	0.638 ± 0.025	0.561 ± 0.073	0.630 ± 0.058
	LC	0.657 ± 0.054	0.582 ± 0.045	0.622 ± 0.039	0.528 ± 0.083	0.577 ± 0.072
	ML	0.580 ± 0.046	0.601 ± 0.025	0.583 ± 0.017	0.560 ± 0.058	0.559 ± 0.051
	PDE	0.592 ± 0.043	0.580 ± 0.026	0.589 ± 0.019	0.526 ± 0.071	0.554 ± 0.052
Avg		0.643 ± 0.044	0.601 ± 0.035	0.603 ± 0.024	0.559 ± 0.090	0.580 ± 0.059
MORPH	ant-1.3	0.606 ± 0.094	0.563 ± 0.091	0.542 ± 0.049	0.643 ± 0.090	0.555 ± 0.108
	arc	0.574 ± 0.070	0.542 ± 0.069	0.565 ± 0.046	0.543 ± 0.099	0.538 ± 0.093
	camel-1.0	0.553 ± 0.072	0.556 ± 0.061	0.534 ± 0.047	0.539 ± 0.090	0.544 ± 0.090
	poi-1.5	0.643 ± 0.047	0.536 ± 0.053	0.517 ± 0.010	0.490 ± 0.091	0.605 ± 0.059
	redaktor	0.606 ± 0.086	0.573 ± 0.105	0.517 ± 0.046	0.507 ± 0.093	0.535 ± 0.090
	skarbonka	0.563 ± 0.119	0.573 ± 0.106	0.494 ± 0.044	0.482 ± 0.101	0.505 ± 0.107
	tomcat	0.595 ± 0.058	0.595 ± 0.041	0.611 ± 0.038	0.508 ± 0.087	0.555 ± 0.086
	velocity	0.661 ± 0.075	0.596 ± 0.086	0.483 ± 0.026	0.500 ± 0.044	0.574 ± 0.094
	xalan-2.4	0.585 ± 0.045	0.584 ± 0.037	0.553 ± 0.025	0.481 ± 0.074	0.571 ± 0.067
	xerces-1.2	0.517 ± 0.019	0.575 ± 0.042	0.523 ± 0.016	0.493 ± 0.036	0.532 ± 0.052
Avg		0.590 ± 0.069	0.569 ± 0.069	0.534 ± 0.035	0.519 ± 0.080	0.551 ± 0.085
Relink	Apache	0.643 ± 0.068	0.521 ± 0.067	0.571 ± 0.070	0.629 ± 0.068	0.621 ± 0.070
	Safe	0.648 ± 0.092	0.574 ± 0.126	0.589 ± 0.101	0.558 ± 0.138	0.627 ± 0.110
	Zxing	0.528 ± 0.025	0.554 ± 0.036	0.553 ± 0.041	0.512 ± 0.063	0.550 ± 0.044
Avg		0.606 ± 0.062	0.550 ± 0.076	0.571 ± 0.071	0.566 ± 0.090	0.599 ± 0.075
Total Avg		0.608 ± 0.061	0.575 ± 0.061	0.559 ± 0.038	0.538 ± 0.085	0.567 ± 0.076

Note. Notice the best AUC in each row is marked in bold. Abbreviations: SCL, simple combined learning; STL, single-task learning.

that for these baseline approaches, we also use logistic regression as the underlying classifier, since the underlying classifier used by MASK is logistic regression. This setting can guarantee that these methods are compared in a fair way.

We further analyze whether the improvement of MASK over baseline approaches are significant based on Wilcoxon signed-rank test⁵⁹ with a Bonferroni correction⁶⁰ for each project. The detailed results are shown in Table 7. If the statistical test shows a significant difference, we then use the Cliff's δ to examine whether the magnitude of the difference is not negligible. In Table 7, the cells in "P-value" column filled with light blue indicates MASK performs significantly better than baseline approaches according to the Wilcoxon signed-rank test with a Bonferroni correction (ie,

TABLE 7 *P* value and Cliff's delta (δ) for comparison results between MASK and the baseline approaches in terms of F1 and AUC

Datasets	Projects	MASK vs STL			MASK vs SCL			MASK vs Peter Filter			MASK vs Burak Filter		
		F1	δ	AUC	F1	δ	AUC	F1	δ	AUC	F1	δ	AUC
AEEEM	EQ	2.39E-08	0.46	2.23E-22	0.80	0.98	1.29E-33	0.99	5.36E-04	0.28	2.42E-03	0.25	1.55E-01
	JDT	2.39E-22	0.80	2.50E-21	0.78	0.74	2.15E-19	0.74	2.72E-28	0.90	9.64E-29	0.91	1.34E-11
	LC	4.44E-26	0.87	1.36E-17	0.70	0.56	1.06E-07	0.44	7.36E-31	0.95	4.10E-22	0.79	8.00E-11
	ML	6.24E-02	-0.15	1.36E-03	-0.26	-0.05	4.10E-01	-0.07	6.07E-02	0.15	1.31E-03	0.26	1.24E-01
MORPH	PDE	9.44E-02	0.14	3.95E-02	0.17	0.05	5.99E-01	0.04	3.66E-08	0.45	4.54E-13	0.59	2.75E-01
	ant-1.3	6.01E-03	0.22	4.90E-03	0.23	0.35	1.41E-06	0.39	3.40E-03	0.25	2.66E-03	-0.25	1.02E-04
	arc	3.65E-05	0.36	2.09E-03	0.25	0.12	4.07E-01	0.07	1.24E-08	0.49	2.27E-02	0.19	7.54E-22
	camel-1.0	5.95E-03	0.10	1.63E-01	-0.11	-0.05	1.47E-01	0.12	1.31E-16	0.80	4.01E-01	0.07	7.88E-16
Relink	poi-1.5	2.84E-31	0.95	2.35E-25	0.85	1.00	1.11E-31	0.96	2.22E-06	0.39	4.39E-26	0.86	4.95E-34
	redaktor	1.72E-04	0.32	1.20E-02	0.21	0.20	4.32E-12	0.57	6.61E-12	0.59	2.53E-10	0.52	2.16E-09
	skarbonka	4.75E-01	-0.17	3.61E-01	-0.07	-0.47	6.73E-08	0.44	3.04E-04	0.30	3.22E-07	0.42	2.82E-08
	tomcat	7.53E-02	0.15	6.36E-01	-0.04	-0.22	7.63E-03	-0.22	4.83E-16	0.67	1.94E-15	0.65	2.13E-13
Zxing	velocity	2.01E-24	0.83	4.17E-08	0.45	0.82	1.70E-32	0.97	1.38E-17	0.70	8.94E-29	0.91	2.55E-34
	xalan-2.4	9.75E-01	0.00	7.63E-01	0.02	0.48	1.50E-08	0.46	5.14E-11	0.54	7.03E-25	0.84	4.83E-04
	xerces-1.2	8.87E-28	-0.93	3.42E-21	-0.77	0.15	1.56E-02	-0.20	5.53E-13	-0.62	7.67E-07	0.40	3.90E-14
	Apache	1.89E-17	0.70	1.12E-22	0.80	0.57	2.87E-14	0.62	7.77E-01	-0.02	1.58E-02	0.20	5.02E-01
Safe	Safe	2.05E-03	0.25	1.88E-06	0.39	0.31	1.08E-06	0.40	1.60E-01	0.12	1.62E-08	0.46	1.82E-01
	Zxing	1.02E-24	-0.89	8.62E-08	-0.44	-0.86	2.37E-07	-0.42	6.97E-14	-0.65	2.30E-01	0.10	4.04E-23
												0.86	3.96E-04

Abbreviations: SCL, simple combined learning; STL, single-task learning.

P value is less than .05). Notice that there are 10×10 results for each comparison between MASK and baselines approaches on a specific project. When MASK is statistically better than baselines, the cells in δ column will be filled with dark gray or light gray based on whether the magnitude of the difference is trivial according to Cliff's δ (ie, filling light gray if effectiveness level is negligible or dark gray if effectiveness level is nonnegligible).

Compared with STL, MASK can achieve better performance across 18 projects in most cases. In terms of F1, MASK achieves average performances of 0.403, 0.374, and 0.462 on AEEEM, MORPH, and ReLink, respectively. MASK has better performance than STL on AEEEM and MORPH. The reason of worse performance on ReLink may arise from the relatively small number of related projects (ie, only three related projects). In terms of AUC, MASK achieves average performances of 0.643, 0.590, and 0.606 on AEEEM, MORPH, and ReLink, respectively.

MASK has better performance than STL on all the datasets on average and has 23.42% improvement over STL at most. According to Table 7, we notice that in most cases, MASK shows significant improvement over the STL with nonnegligible effect size in terms of both F1 and AUC performance measures.

Compared with SCL, MASK can achieve better performance on average. In terms of F1, MASK achieves performances of 0.403, 0.374, and 0.462 on AEEEM, MORPH, and ReLink, respectively. MASK has better performance than SCL except for ReLink on average and has 49.25% improvement over SCL. In terms of AUC, MASK performs better than SCL in most cases and has 36.85% improvement at most. According to Table 7, we notice that in most cases, MASK shows significant improvement over SCL and has nonnegligible effect size when considering both F1 and AUC performance measures.

Compared with Peters filter, MASK can achieve better performance on average. In terms of F1, MASK achieves performances of 0.403, 0.374, and 0.462 on AEEEM, MORPH, and ReLink, respectively. MASK has better performance than Peters filter except for ReLink on average and has 33.67% improvement over Peters filter. In terms of AUC, MASK performs better than Peters filter for each project and improves Peters filter by 32.20% of AUC at most. According to Table 7, we notice that in most cases, MASK shows significant improvement over Peters filter and has nonnegligible effect size when considering both F1 and AUC performance measures.

Compared with Burak filter, MASK still achieves better performance on average. In terms of F1, MASK achieves performances of 0.403, 0.374, and 0.462 on AEEEM, MORPH, and ReLink, respectively. MASK has better performance than Burak filter except for ReLink on average and has 35.96% improvement over Burak filter. In terms of AUC, MASK performs better than Burak filter for nearly all the projects. The results of MASK on average are better than Burak filter across 18 projects and have 16.52% improvement over Burak filter at most. According to Table 7, we notice that in most cases, MASK shows significant improvement over Burak filter and has nonnegligible effect size when considering both F1 and AUC performance measures.

In this RQ, we assume only 10% of modules are labeled for each project. The number of 10% modules in ReLink, AEEEM, and MORPH varies from 19 to 40, 32 to 150, and 13 to 72, respectively. Therefore, it is not hard to find that our MASK only requires a small amount of labeled data, and it can achieve competitive performance based on the above result analysis.

In addition, STL only uses limited data from the target project, and SCL simply combines the labeled data from other related projects. Both of them (ie, STL and SCL) ignore the relatedness among all related projects. However, MASK builds multiple prediction models simultaneously by utilizing the relatedness among all related projects. By comparing the performance value with STL and SCL, we can find that MASK can outperform these two methods significantly, which indicates, to some extent, MASK can mine the relatedness among related projects successfully and then improve the prediction performance.

For a new usage scenario that both the source and target projects have limited labeled data, our proposed approach MASK, which builds prediction models for related projects simultaneously, has better performance than state-of-the-art baseline approaches (ie, STL, SCL, Peters filter, and Burak filter). These promising results show that MASK can effectively extract and utilize shared information in related projects when building prediction models.

RQ2:How does the number of labeled modules affect the performance of MASK?

Motivation. Our proposed new usage scenario has the issue that both the source project and the target projects have limited labeled modules. In RQ1, we use inverse 10-fold CV to simulate the new scenario with insufficient labeled modules. That is, by default, we only set the percentage of labeled modules as 10%. But the performance of our approach may vary when the percentage of the labeled modules is different. Therefore, we want to investigate the influence of different percentages of labeled modules on the performance of MASK.

Approach. To answer this RQ, we perform two additional experiments on another two settings: inverse fivefold CV and inverse twofold CV. That is, we will investigate the performance of MASK when the percentage of labeled trained data is set as 10%, 20%, and 50%, respectively.

Results. Table 8 presents the average F1 and AUC across the 18 projects with various percentages of labeled modules as the training data. In Table 8, the first column presents the name of datasets. The second column lists related projects for each datasets. The following six columns are divided into two groups for F1 and AUC performance measures. In each group, there are three settings representing the percentages of labeled modules for MASK, which can illustrate the average performance and stability of trained models. The average values of 100 runs are listed at the end of each dataset.

TABLE 8 The Performance of MASK when considering different percentage of labeled modules in terms of F1 and AUC

Datasets	Related Projects	F1			AUC		
		10%	20%	50%	10%	20%	50%
AEEEM	EQ	0.574 ± 0.061	0.574 ± 0.074	0.597 ± 0.057	0.677 ± 0.027	0.678 ± 0.034	0.688 ± 0.029
	JDT	0.539 ± 0.090	0.540 ± 0.097	0.564 ± 0.062	0.709 ± 0.052	0.708 ± 0.052	0.717 ± 0.037
	LC	0.365 ± 0.071	0.378 ± 0.078	0.406 ± 0.062	0.657 ± 0.054	0.658 ± 0.052	0.665 ± 0.044
	ML	0.255 ± 0.102	0.243 ± 0.093	0.245 ± 0.097	0.580 ± 0.046	0.574 ± 0.035	0.575 ± 0.041
	PDE	0.284 ± 0.100	0.282 ± 0.112	0.302 ± 0.094	0.592 ± 0.043	0.590 ± 0.047	0.598 ± 0.044
Avg		0.403 ± 0.085	0.403 ± 0.091	0.423 ± 0.075	0.643 ± 0.044	0.642 ± 0.044	0.649 ± 0.039
MORPH	ant-1.3	0.338 ± 0.137	0.350 ± 0.132	0.391 ± 0.123	0.606 ± 0.094	0.626 ± 0.085	0.631 ± 0.098
	arc	0.270 ± 0.111	0.285 ± 0.121	0.256 ± 0.111	0.574 ± 0.070	0.587 ± 0.070	0.567 ± 0.063
	camel-1.0	0.185 ± 0.080	0.211 ± 0.067	0.200 ± 0.032	0.553 ± 0.072	0.560 ± 0.070	0.510 ± 0.037
	poi-1.5	0.733 ± 0.037	0.749 ± 0.024	0.760 ± 0.035	0.643 ± 0.047	0.667 ± 0.026	0.679 ± 0.030
	redaktor	0.360 ± 0.140	0.415 ± 0.113	0.529 ± 0.089	0.606 ± 0.086	0.638 ± 0.078	0.705 ± 0.050
	skarbonka	0.327 ± 0.136	0.346 ± 0.123	0.361 ± 0.103	0.563 ± 0.119	0.581 ± 0.100	0.574 ± 0.090
	tomcat	0.256 ± 0.102	0.288 ± 0.081	0.319 ± 0.069	0.595 ± 0.058	0.608 ± 0.042	0.615 ± 0.037
	velocity	0.858 ± 0.038	0.873 ± 0.034	0.883 ± 0.031	0.661 ± 0.075	0.711 ± 0.042	0.734 ± 0.042
	xalan-2.4	0.279 ± 0.106	0.297 ± 0.087	0.327 ± 0.070	0.585 ± 0.045	0.592 ± 0.037	0.603 ± 0.034
	xerces-1.2	0.138 ± 0.059	0.107 ± 0.050	0.103 ± 0.056	0.517 ± 0.019	0.512 ± 0.014	0.510 ± 0.017
Avg		0.375 ± 0.095	0.392 ± 0.083	0.413 ± 0.072	0.590 ± 0.069	0.608 ± 0.056	0.613 ± 0.050
Relink	Apache	0.617 ± 0.052	0.630 ± 0.044	0.628 ± 0.058	0.643 ± 0.068	0.668 ± 0.038	0.689 ± 0.033
	Safe	0.545 ± 0.141	0.559 ± 0.128	0.602 ± 0.095	0.648 ± 0.092	0.672 ± 0.061	0.691 ± 0.068
	Zxing	0.225 ± 0.109	0.227 ± 0.111	0.215 ± 0.089	0.528 ± 0.025	0.532 ± 0.026	0.533 ± 0.018
Avg		0.462 ± 0.101	0.472 ± 0.094	0.482 ± 0.081	0.606 ± 0.062	0.624 ± 0.042	0.638 ± 0.040
Total Avg		0.397 ± 0.937	0.409 ± 0.089	0.427 ± 0.076	0.608 ± 0.058	0.620 ± 0.047	0.627 ± 0.043

Note. Notice the best F1 and AUC are marked in bold.

In terms of F1, the average values vary from 0.138 to 0.858, 0.107 to 0.873, and 0.103 to 0.883 by using 10%, 20%, and 50% modules that are labeled. With the increase in the number of labeled modules, the performance of MASK is improved. For example, MASK on average can achieve 0.397, 0.407, and 0.427 by using 10%, 20%, and 50% modules that are labeled.

In terms of AUC, the average values vary from 0.517 to 0.709, 0.512 to 0.711, and 0.510 to 0.734 by using 10%, 20%, and 50% modules that are labeled. We notice that the average performance of MASK improves when the number of available labeled modules increases. These results varies from 0.510 to 0.734, which is relatively stable.

Notice that some datasets only have limited modules and the increase in the number of modules is quite small when the percentage arises from 10% to 20%. Therefore, the improvement of the performance is very small or even no when considering two different percentages. However, the increase in the number of modules is large when the percentage arises from 10% to 50%, and the improvement of the performance is high. This indicates more labeled modules will result in higher performance of MASK.

In general, the more the number of available labeled modules, the higher performance of MASK. Therefore, high-quality dataset is a key for MASK to achieving good performance.

4.5 | Threats to validity

In this subsection, we mainly discuss the potential threats to validity of our empirical studies.

Threats to the external validity of our study are that the observed experimental results may not be applicable to other software projects. To guarantee the representative of experimental subjects, we choose the three extensively used datasets AEEEM, MORPH, and ReLink.^{39,41,52,61-63}

In addition, we choose logistic regression as the underlying classifier for MASK and other four baseline approaches. Since logistic regression is the most used classifier in previous SDP research.^{24,26,37}

Threats to the internal validity are that defects may exist in the implementation of these approaches. To minimize the internal threats, we review the codes by pair programming and make full use of mature third-party libraries such as MALSAR.⁶⁴

Threats to the construct validity are that the performance evaluation may not be representative of the real-world requirements for SDP. To minimize the threats, we use the F1 measure, which has been widely used in current SDP studies^{37,39,52,61,65-68} and makes a good balance between the precision and recall measures. AUC measure has also been widely used in current studies for SDP since it is insensitive to class imbalanced data and does not depend on an arbitrarily selected threshold.^{41,45}

5 | DISCUSSION

5.1 | Some limitations of MASK

WPDP assumes that we have sufficient labeled data from the same project, while CPDP assumes that we have plenty of labeled data from source projects. However, in practice, we might only have limited labeled data from both the source and target projects in some scenarios. Therefore, in this paper, we propose a new scenario, in which both the source project and the target project have limited labeled data. Then we proposed a novel multitask defect prediction approach MASK based on MTL. To verify the effectiveness of MASK, we design and conduct experimental studies on 18 widely used real-world projects. In our experiments, all the projects to be predicted are treated as the target projects. Besides, to simulate that each target project only has a few labeled data, we propose a new experimental setting (ie, inverse 10-fold CV), which means that only 10% of modules are labeled and the remaining 90% of modules are not labeled.

Based on the finally experimental results, we find several limitations for MASK. First, MASK can perform significantly better than the state-of-the-art baselines, but the improvements over baselines are not very large. One of the potential reasons is the limited labeled data for some projects. For example, Apache has 19 labeled modules, Safe has six labeled modules, and ZXing has 40 labeled modules, respectively, when we use 10% labeled modules to build multiple prediction models. However, we think this new scenario is important and can find applications in real software development. In the future, we encourage more researchers to propose more novel solutions (ie, solutions based on MTL) to further improve the performance. Second, MASK can outperform STL by utilizing the relatedness between all projects. However, when applying MTL to this scenario, it is a challenge to measure the relatedness for different projects. In this paper, we simply consider two heuristics for measuring the relatedness. One is whether these projects are developed by the same organization. The other is whether these projects consider the same metrics (ie, features) to measure the extracted program modules. Finding more effective methods to measure the relatedness for different projects can help to improve the performance of our proposed MASK method. This is an open problem, and we encourage more researchers to investigate this issue in the future.

5.2 | Computational cost analysis

MASK consists of a DEO phase and a MTL phase. The former phase aims to find optimal weights for shared and nonshared information in related projects, while the latter phase builds prediction models for each project simultaneously. The former phase is time-consuming, and we want to analyze the computational cost of our method MASK and make a comparison between MASK and all baseline methods. We collect the sum of running time of $10 \times$ inverse 10-fold CV for each baseline method and MASK on three datasets. Notice that the gathered running time includes data preprocessing, model construction on the training set and the model application on the testing set. All the methods experimented in this paper are executed on CentOS Linux 7 (Memory: 32 GB, Processor: Intel Xeon(R) CPU E5-2609 v2 @ 2.50 GHz \times 8). The final results can be found in Table 9.

TABLE 9 Computational cost of different methods on AEEEM, MOPRH, and ReLink (unit: second)

Datasets	Related Projects	MASK	STL	SCL	Peters Filter	Burak Filter
AEEEM	EQ	709.87	1.16	5.32	183.92	230.42
	JDT		2.86	6.04	134.83	265.64
	LC		2.36	3.79	153.42	276.03
	ML		3.78	12.41	164.03	440.74
	PDE		3.49	9.20	207.10	521.41
Sum		709.87	13.64	36.77	843.30	1734.24
MORPH	ant-1.3	556.63	1.21	1.24	58.52	80.25
	arc		1.34	1.31	60.09	119.16
	camel-1.0		1.47	1.40	61.46	119.21
	poi-1.5		1.49	1.73	69.06	129.58
	redaktor		1.34	1.05	55.99	92.80
	skarbonka		1.19	0.56	47.41	51.48
	tomcat		2.22	4.56	82.31	229.81
	velocity		1.37	1.17	63.95	95.69
	xalan-2.4		1.62	4.32	76.91	207.80
	xerces-1.2		1.82	2.51	76.45	157.39
Sum		556.63	15.08	19.84	652.15	1283.17
Relink	Apache	269.88	1.09	0.30	10.82	18.45
	Safe		0.92	0.13	10.63	12.36
	Zxing		1.14	0.62	9.86	28.35
Sum		269.88	3.16	1.05	31.31	59.16
Total		1536.37	31.88	57.66	1526.76	3076.57

Abbreviations: SCL, simple combined learning; STL, single-task learning.

Datasets	Projects	F1			AUC		
		MASK	Random	Improvement, %	MASK	Random	Improvement, %
AEEEM	EQ	0.574	0.501	15	0.677	0.584	16
	JDT	0.539	0.318	69	0.709	0.628	13
	LC	0.365	0.154	137	0.657	0.537	22
	ML	0.255	0.214	19	0.580	0.529	10
	PDE	0.284	0.189	50	0.592	0.513	15
Average		0.403	0.275	47	0.643	0.558	15

TABLE 10 Comparison between the performance of MASK tuned by DEO and the performance of MASK configured randomly on AEEEM

Abbreviation: DEO, differential evolution optimization.

In Table 9, the first column lists the project name, and the second column lists the project names. The following five columns represent five methods investigated in this paper, respectively. Notice that the running time in each cell represents the total time of $10 \times$ inverse 10-fold CV. For MASK, we report the total running time for each dataset since all prediction models are built simultaneously. Besides, we also report the total running time of each method on each dataset.

From Table 9, we can find that SCL and STL need the least time to build a prediction model and make corresponding performance evaluation. However, MASK, Peters filter, and Burak filter need much more time than STL and SCL. In particular, Burak filter needs the most time to build a prediction model and makes performance evaluation in most cases. Therefore, the computational cost of MASK is acceptable.

5.3 | The influence of tuning hyperparameters

According to the results in Section 4.4, by comparing the performance value with STL and SCL, we can find that MASK can outperform the two baseline methods significantly, which indicates, to some extent, MASK can learn the relatedness among related projects successfully and then improve the prediction performance. To further analyze the improvement of performance contributed by the tuned configuration in each training model, we conduct additional experiments to compare the performance before and after we tune the hyperparameters in MASK. The comparison results on AEEEM can be found in Table 10.

In Table 10, the first column lists the dataset name and the second column lists the project names. The following six columns represent the performances of MASK tuned by DEO and MASK configured randomly in terms of F1 and AUC, respectively. Since there exists randomness in MASK and Random, we run these methods 10 times and report the average value of these 10 runs. In the last row, we report the average performance and the percent of performance improvement. According to the results shown in Table 10, we can find that MASK tuned by DEO can obtain better performance and improve MASK configured randomly by 47% and 15% in terms of F1 and AUC on average, respectively. In addition, we draw the similar conclusions on ReLink and MORPH. Therefore, the tuned configuration in MASK can improve the performance of MASK.

6 | RELATED WORK

Since the target software projects usually lack the labeled modules, a possible solution is to use other historical projects with labeled modules to train the prediction models. This issue is called the CPDP.^{6,39,41,65,69-75} However, the dataset distribution of the target and source projects is usually different, which makes CPDP a challenging task. Zimmermann et al²⁷ conducted a large-scale empirical study to investigate the feasibility of CPDP, and their results were not optimistic.

Therefore, researchers proposed new methods to improve the performance of CPDP. Turhan et al¹⁶ proposed Burak filter that selects k (ie, 10) nearest modules in the source projects for each module in the target project. Peters et al³⁷ improved the filter mechanism, which took in the infrastructure of source projects. Ma et al⁶⁵ proposed a method that assigns higher weights to the source modules that are similar to the target modules.

Wang et al⁶⁶ leveraged a representation-learning algorithm (ie, deep learning) to learn semantic representation of the modules from the projects. Chen et al³⁸ proposed a novel algorithm to remove negative modules from the source projects.

Xia et al²⁶ proposed a two-layer framework Hydra, which combined the genetic algorithm and ensemble learning to capture general properties between the source and target projects and merits of multiple prediction models.

Some researchers investigate heterogeneous CPDP, which assumes that the source and target projects have different feature sets. Nam and Kim⁶² proposed the heterogeneous CPDP method, including feature selection phase and feature mapping phase. Jing et al⁵² solved the problem by defining unified feature space and applying canonical correlation analysis (CCA)-based transfer learning.

Other researchers considered unsupervised learning methods.

Nam and Kim⁶¹ performed defect prediction on unlabeled data using a cluster based method that has two phases. They further used feature selection and module selection to remove noises in dataset to improve CLA and proposed CLAMI. Zhang et al⁶³ designed a connectivity-based unsupervised prediction model. Recently, Zhou et al⁴¹ proposed two unsupervised method (ManualDown and ManualUp), and they suggested that these two simple methods should be set as baseline methods in the future CPDP research.

More studies can be found in a recent systematic literature review and meta-analysis on CPDP.⁶ Different from previous studies, we firstly propose a new usage scenario, which both source and target projects have limited labeled data. Then we propose a MASK approach based on MTL. Empirical results on 23 real-world software projects show the effectiveness of our proposed approach.

7 | CONCLUSION AND FUTURE WORK

In this paper, we propose a new usage scenario and then proposed a novel approach MASK, which mainly based on MTL. MASK has two phases: DEO phase and MTL phase. The former phase is used to search for the optimal value of regularization parameters for both the shared information and nonshared information. The latter phase uses the optimal value of regularization parameters to build models simultaneously and outputs models for each project. To show the effectiveness of MASK, we conduct empirical studies on 18 real-world projects. The experiment results show that MASK can outperform state-of-the-art baseline approaches in most cases.

Our initial solution based on MTL is promising although not perfect. Therefore, our study can inspire more researchers to propose advanced solutions for this usage scenario. In the future, we plan to evaluate MASK with datasets from more commercial and open-source projects. Moreover, we also want to improve the performance of MASK by designing more effective ways to measure the relatedness of different projects.

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